



PATENT

Cofc

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Tom Tse, et al. 10,082,567
Assignee: Advanced Mirco Devices, Inc.
Title: METHOD AND SYSTEM FOR DOSE CONTROL DURING AN ION
IMPLANTATION PROCESS
Patent No.: 6,797,967 B1 Issued: September 28, 2004
Atty. Docket No.: 1458-TT4763

MS: Certificate of Correction Branch
COMMISSIONER FOR PATENTS
PO Box 1450
Alexandria, VA 22313-1450

**REQUEST FOR CERTIFICATE OF CORRECTION OF PATENT—
PTO MISTAKE (37 C.F.R. § 1.322(a))**

Dear Sir:

Pursuant to 35 U.S.C. § 254 and 37 C.F.R. § 1.322(a), please issue a Certificate of Correction in the above-identified matter. The mistake(s) to be corrected was made by the Office.

1. Attached hereto is Form PTO-1050.
2. The exact page(s) and line number(s) where the error(s) is shown correctly in the application file:
Response to Office Action filed on April 20, 2004; page 4 of 6; Claim 21 (now Claim 18).
3. Please send the Certificate to:

J. Gustav Larson
TOLER, LARSON & ABEL, LLP
5000 PLAZA ON THE LAKE, SUITE 265
AUSTIN, TX 78746

Certificate
OCT 22 2004
of Correction

Respectfully submitted,

10-11-04
Date

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**UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION**

PATENT NO. : 6,797,967 B1

DATED : September 28, 2004

INVENTOR(S) : Tom Tse, Zhiyong Zhao, David M. Hendrix

It is certified that error appears in the above-identified patent and that said Letters Patent
is hereby corrected as shown below:

Column 10, Line 20, please change "claim 7" to "claim 17."

MAILING ADDRESS OF SENDER:

TOLER, LARSON & ABEL
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Austin, TX 78746

PATENT NO. 6,797,967

No. of additional copies



This collection of information is required by 37 CFR 1.322, 1.323, and 1.324. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 1.0 hour to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Attention Certificate of Corrections Branch, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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OCT 25 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Tom Tse et al.

Title: METHOD AND SYSTEM FOR DOSE CONTROL DURING AN ION
IMPLANTATION PROCESS

App. No.: 10/082,567 Filed: 02/25/2002

Examiner: Mary A. El Shammaa Group Art Unit: 2881

Customer No.: 34456 Confirmation No.: 3170

Atty. Dkt. No.: 1458-TT4763

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

RESPONSE AFTER FINAL

Dear Sir:

In response to the Final Action mailed November 20, 2003, and to the Advisory Action mailed March 15, 2004, please amend the above-identified application as follows:

CERTIFICATE OF TRANSMISSION/MAILING	
I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to the Commissioner for Patents on <u>4-20-04</u> .	
<u>KATRINA PRATI</u>	<u>KATRINA PRATI</u>
Typed or Printed Name	Signature

12. (Previously Presented) The method of claim 6, wherein the second detector is moveable and sited adjacent to the target position during measurement.

13. (Previously Presented) The method of claim 6, wherein the second detector is fixed in place and sited behind the target position.

14. (Previously Presented) The method of claim 6, wherein the second detector is moveable and sited behind the target position.

15. (Previously Presented) The method of claim 6, wherein the second detector is sited along the beam path to the target position.

16. (Original) The method of Claim 6, wherein the reference ratio is in the range of approximately 100:1 to 1:1.

17. (Previously Presented) The method of claim 16, wherein the range of the reference ratio is dependent upon the location of a first detector with reference to a second detector.

18. (Original) The method of Claim 16, wherein the reference ratio may be a previously stored value retrieved from control software.

19. (Canceled)

20. (Canceled)

21. (Previously Presented) The system of claim 22, wherein a characteristic is selected from a group consisting of: beam current, beam energy, beam scan rate, vacuum, gas pressure, and ion dose.

22. (Previously Presented) A system comprising:
memory;
a processor operably connected to said memory;